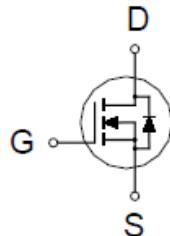
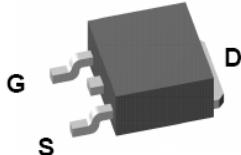


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PRODUCT SUMMARY

$V_{(BR)DSS}$	$R_{DS(ON)}$	I_D
20V	14mΩ @ $V_{GS} = 4.5V$	45A



TO-252

ABSOLUTE MAXIMUM RATINGS ($T_C = 25^\circ C$ Unless Otherwise Noted)

PARAMETERS/TEST CONDITIONS	SYMBOL	LIMITS	UNITS
Gate-Source Voltage	V_{GS}	±12	V
Continuous Drain Current $T_C = 25^\circ C$	I_D	45	A
$T_C = 100^\circ C$	I_D	19	
Pulsed Drain Current ¹	I_{DM}	140	
Avalanche Current	I_{AS}	33	
Avalanche Energy	E_{AS}	52	mJ
Power Dissipation $T_C = 25^\circ C$	P_D	48	W
$T_C = 100^\circ C$	P_D	19	
Operating Junction & Storage Temperature Range	T_J, T_{STG}	-55 to 175	°C

THERMAL RESISTANCE RATINGS

THERMAL RESISTANCE	SYMBOL	TYPICAL	MAXIMUM	UNITS
Junction-to-Case	$R_{\theta JC}$	2.6	110	°C / W
Junction-to-Ambient	$R_{\theta JA}$			

¹Pulse width limited by maximum junction temperature.

²Duty cycle≤1%

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ELECTRICAL CHARACTERISTICS ($T_C = 25^\circ\text{C}$, Unless Otherwise Noted)

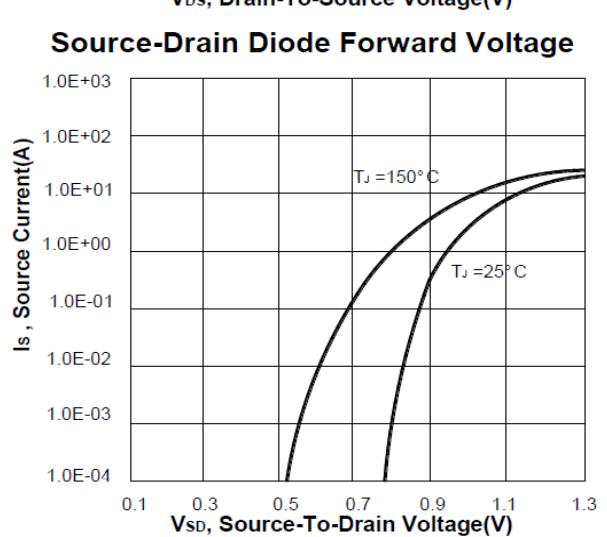
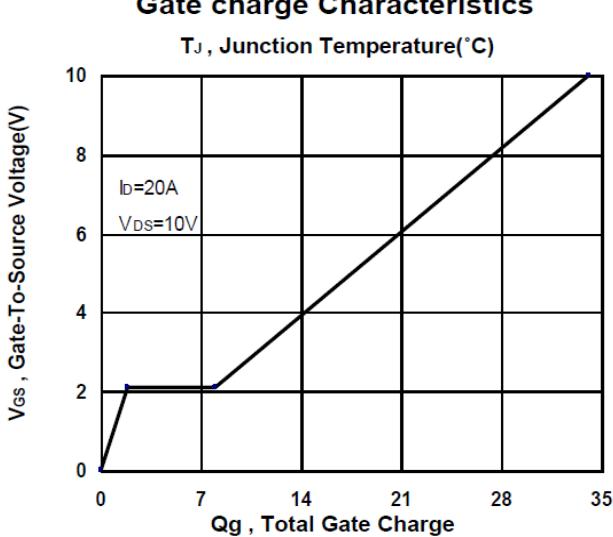
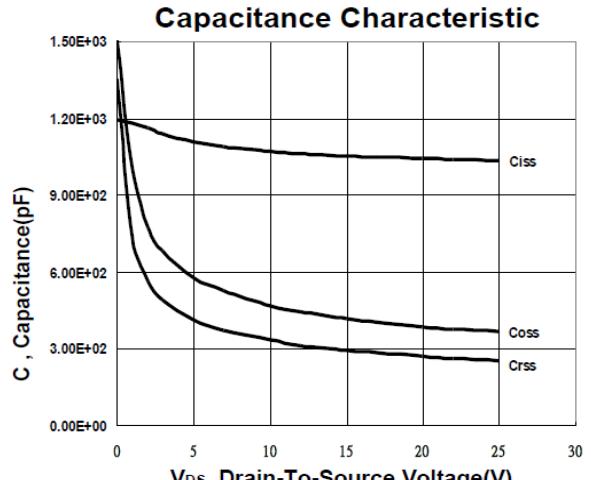
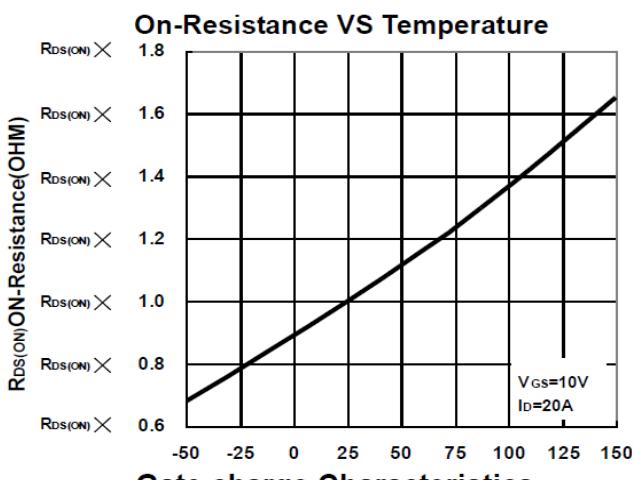
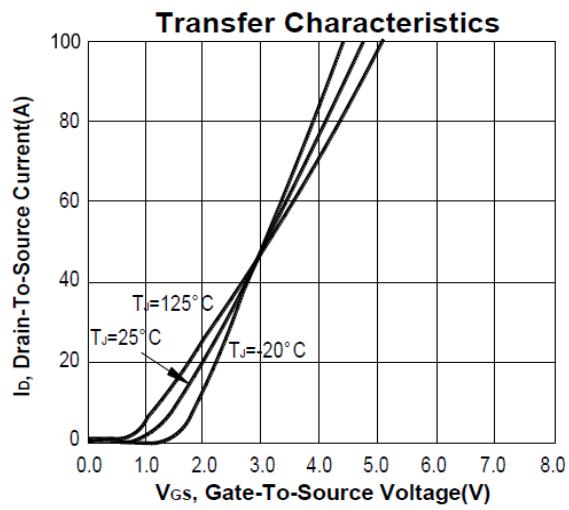
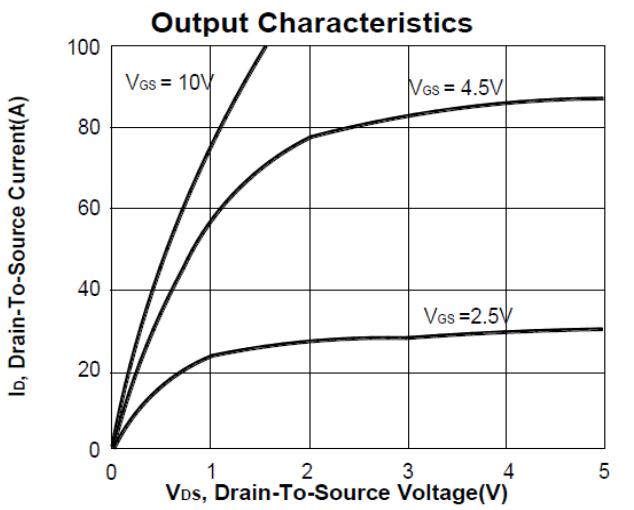
PARAMETER	SYMBOL	TEST CONDITIONS	LIMITS			UNITS
			MIN	TYP	MAX	
STATIC						
Drain-Source Breakdown Voltage	$V_{(\text{BR})\text{DSS}}$	$V_{GS} = 0V, I_D = 250\mu\text{A}$	20			V
Gate Threshold Voltage	$V_{GS(\text{th})}$	$V_{DS} = V_{GS}, I_D = 250\mu\text{A}$	0.45	0.63	1.25	
Gate-Body Leakage	I_{GSS}	$V_{DS} = 0V, V_{GS} = \pm 12V$			± 100	nA
Zero Gate Voltage Drain Current	I_{DSS}	$V_{DS} = 16V, V_{GS} = 0V$			1	μA
		$V_{DS} = 13.2V, V_{GS} = 0V, T_J = 125^\circ\text{C}$			10	
On-State Drain Current ¹	$I_{D(\text{ON})}$	$V_{DS} = 5V, V_{GS} = 4.5V$	140			A
Drain-Source On-State Resistance ¹	$R_{DS(\text{ON})}$	$V_{GS} = 2.5V, I_D = 9A$		12.5	28	$\text{m}\Omega$
		$V_{GS} = 4.5V, I_D = 18A$		9.3	14	
		$V_{GS} = 10V, I_D = 20A$		7.9	12	
Forward Transconductance ¹	g_{fs}	$V_{DS} = 10V, I_D = 20A$		26		S
DYNAMIC						
Input Capacitance	C_{iss}	$V_{GS} = 0V, V_{DS} = 10V, f = 1\text{MHz}$		1030		pF
Output Capacitance	C_{oss}			364		
Reverse Transfer Capacitance	C_{rss}			253		
Total Gate Charge ²	Q_g	$V_{DS} = 0.5V_{(\text{BR})\text{DSS}}, V_{GS} = 5V, I_D = 18A$		34		nC
Gate-Source Charge ²	Q_{gs}			2		
Gate-Drain Charge ²	Q_{gd}			6		
Turn-On Delay Time ²	$t_{d(\text{on})}$	$V_{DS} = 10V, I_D \approx 18A, V_{GS} = 5V, R_{GS} = 3.3\Omega$		7.5		nS
Rise Time ²	t_r			83		
Turn-Off Delay Time ²	$t_{d(\text{off})}$			18		
Fall Time ²	t_f			23		
SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS ($T_C = 25^\circ\text{C}$)						
Continuous Current	I_S				22	A
Forward Voltage ¹	V_{SD}	$I_F = I_S, V_{GS} = 0V$			1.3	V
Reverse Recovery Time	t_{rr}			37		nS
Reverse Recovery Charge	Q_{rr}			43		nC

¹Pulse test : Pulse Width $\leq 300\ \mu\text{sec}$, Duty Cycle $\leq 2\%$.

²Independent of operating temperature.

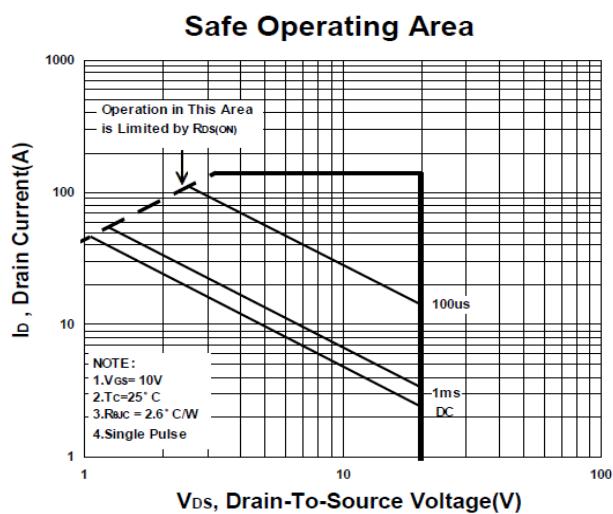
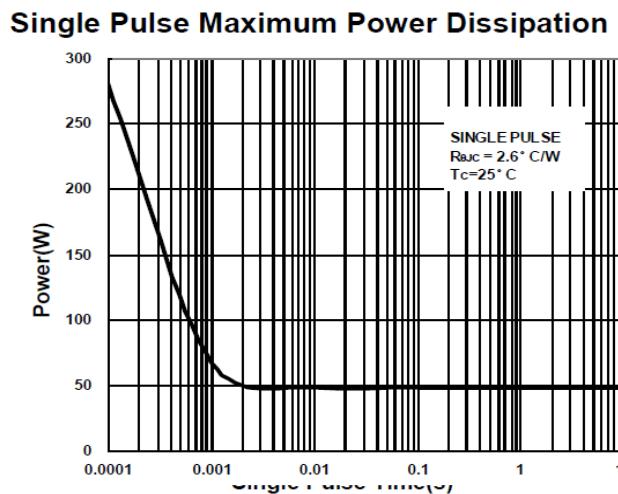
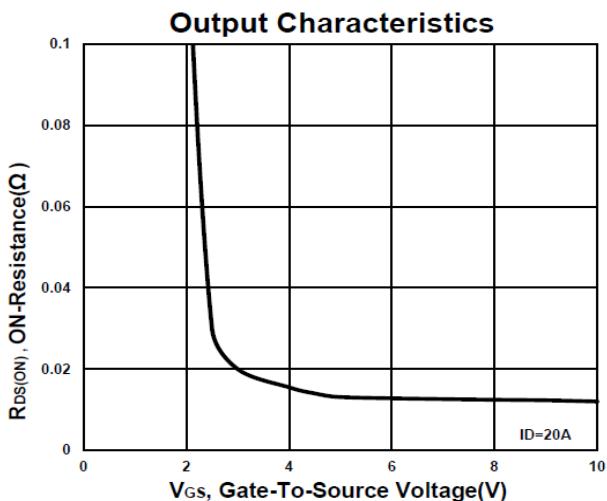
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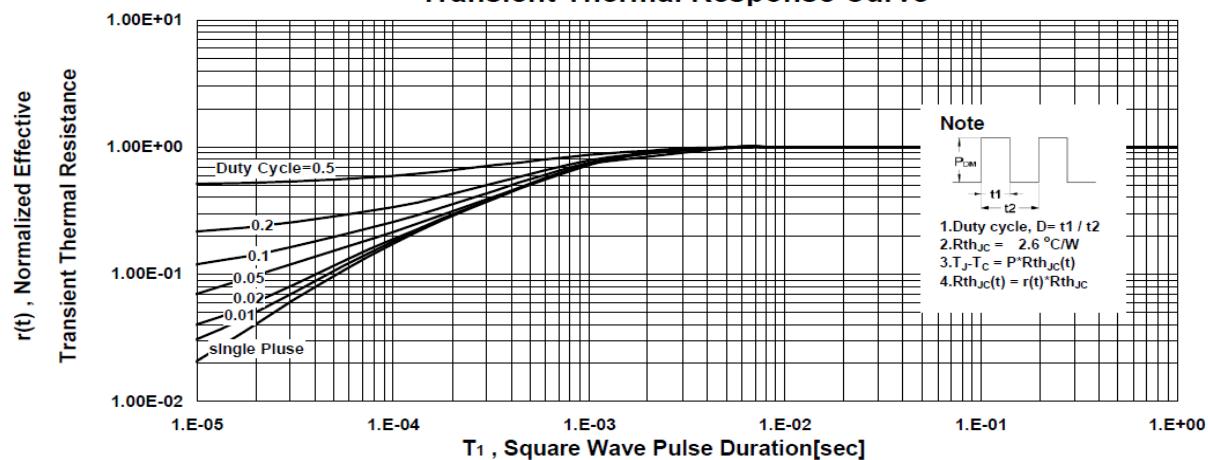


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Transient Thermal Response Curve



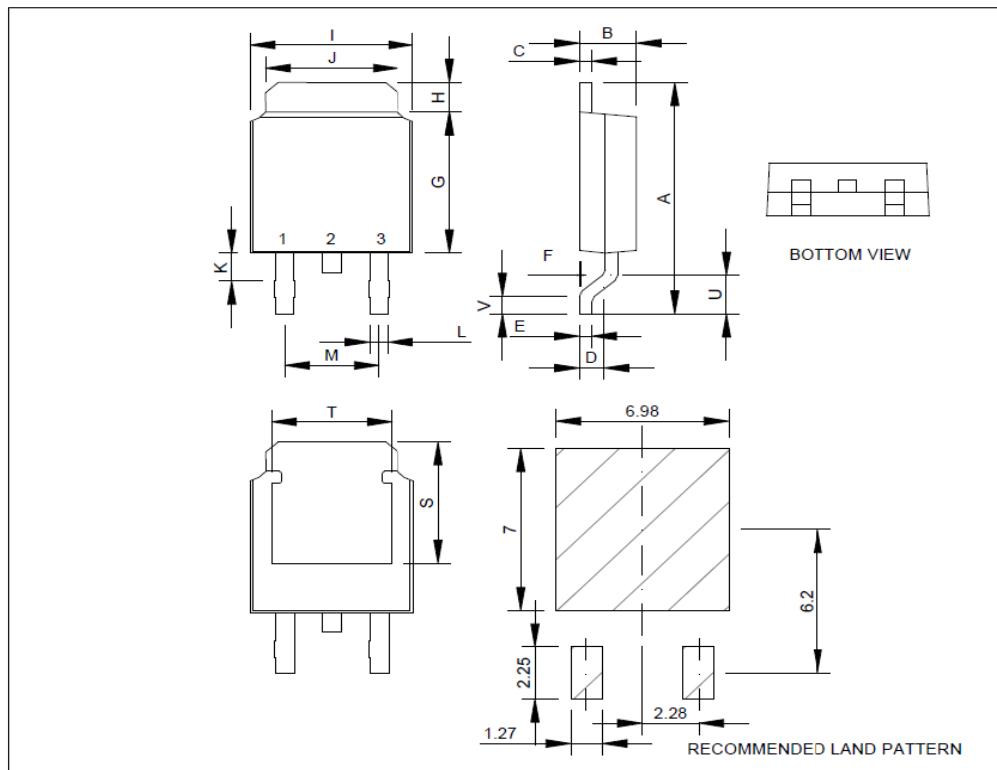
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Package Dimension

TO-252 (DPAK) MECHANICAL DATA

Dimension	mm			Dimension	mm		
	Min.	Typ.	Max.		Min.	Typ.	Max.
A	8.9	10	10.41	J	4.8		5.64
B	2.1	2.2	2.4	K	0.15		1.1
C	0.4	0.5	0.61	L	0.4	0.76	0.89
D	0.82	1.2	1.5	M	4.2	4.58	5
E	0.4	0.5	0.61	S	4.9	5.1	5.3
F	0		0.2	T	4.6	4.75	5.44
G	5.3	6.1	6.3	U	1.4		1.78
H	0.9		1.7	V	0.55	1.25	1.7
I	6.3	6.5	6.8				



*因为各家封装模具不同而外观略有差异，不影响电性及Layout。